[EXTERNAL TEST LOAD/DATA] CONCEPTS

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IBIS QUALITY TASK GROUP

Status:

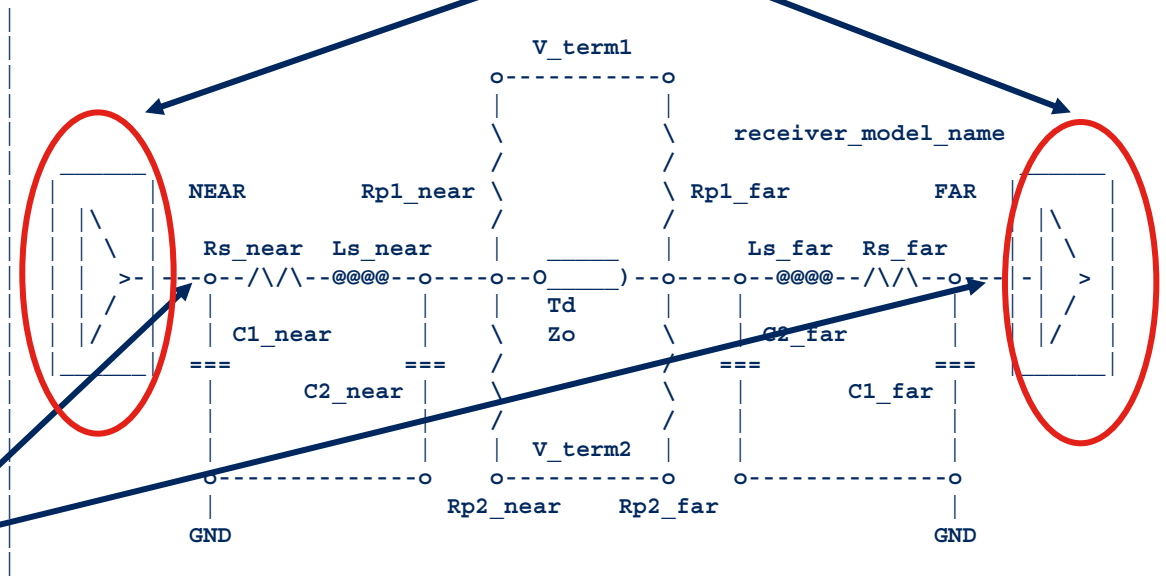
- Correlation discussion put on hold for now
- A BIRD draft to improve the [Test Data] and [Test Load] structures of the IBIS spec was introduced by Anders Ekholm and is currently discussed
- An [External Test Load/ Test Data] BIRD has been drafted by Anders Ekholm (Ericsson) and Mike LaBonte (Cisco systems)
- This BIRD draft is the current topic of weekly IQ meetings

[EXTERNAL TEST LOAD/DATA] CONCEPTS

[Test Load] limitations

- Size of [Test Data] (internal to IBIS file)
- [Test Data] limited to single edge stimuli (no pulse train)
- [Test Load] limited to a fixed topology (inflexible)
- Limited differential load support

Buffer models
Without pin parasitics



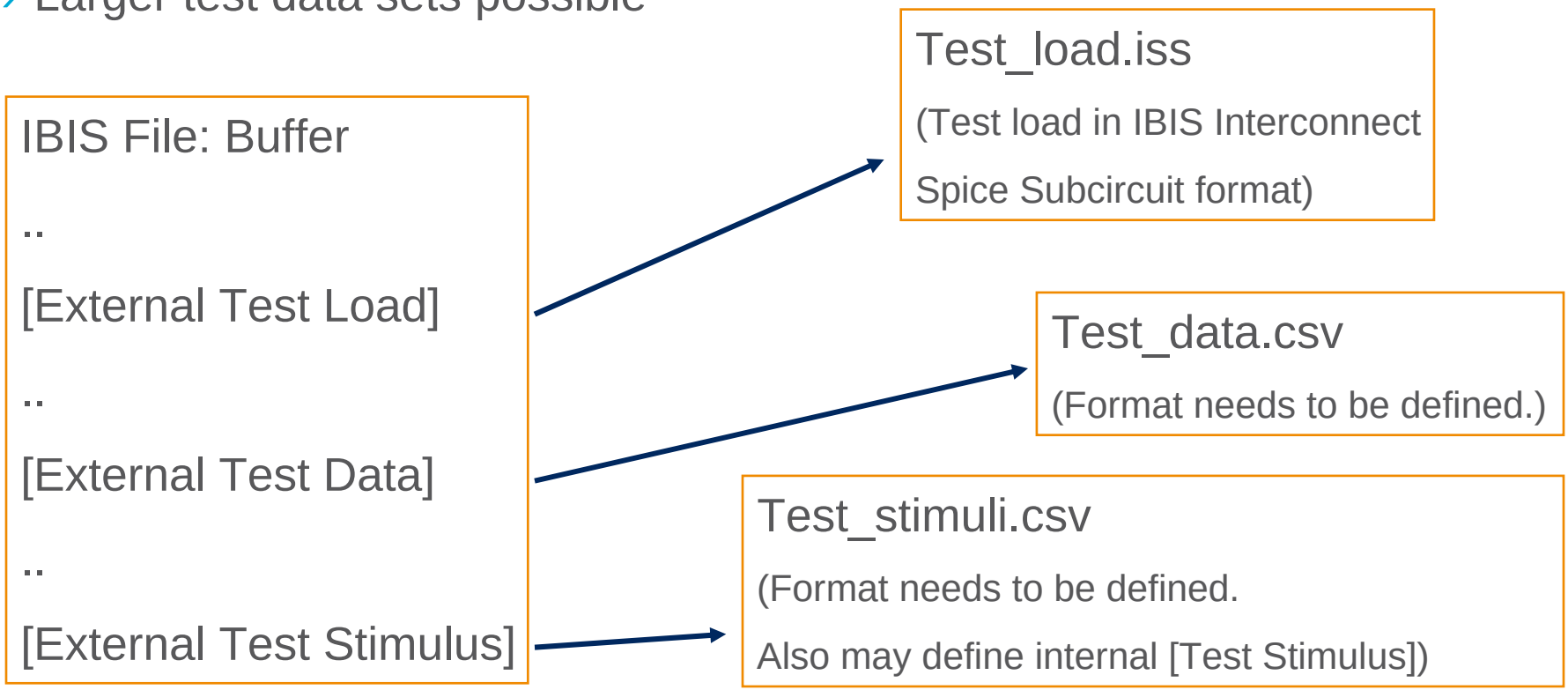
›Bench measured [Test Data] usually can not be measured at pad

[Test Load] has probe points only at pads

[EXTERNAL TEST LOAD/DATA] CONCEPTS

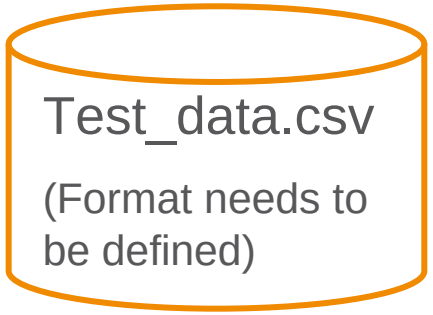
Improvements over [Test Load] / [Test Data]

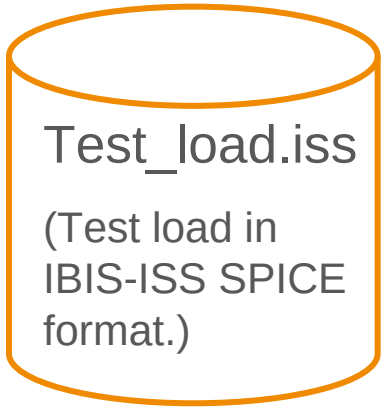
- Full pulse train stimulus
- More general/flexible test load topology
- Larger test data sets possible



[EXTERNAL TEST LOAD/DATA] CONCEPTS

- [External Test Data]
  - Kept in a separate file, size not as limiting
  - Support more than two probe points
- [External Test Load]
  - Support more than two probe points
  - Any load supported by IBIS-ISS can be used
  - Probe points defined as .subckt terminals
  - Easily re-used for many models
- [External Test Stimulus]
  - Any pulse train possible
  - Idealized transition times used (no rise/fall time)





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